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STUDY OF BULK AND ELEMENTARY SCREW DISLOCATION ASSISTED REVERSE BREAKDOWN IN LOW-VOLTAGE: PART 1: DC PROPERTIES



Study of Bulk and Elementary Screw Dislocation Assisted Reverse Breakdown in Low-Voltage: Part 1: DC Properties

NASA Technical Reports Server (NTRS), et al., Philip G. Neudeck

BiblioGov. Paperback. Book Condition: New. This item is printed on demand. Paperback. 28 pages. Dimensions: 9.7in. x 7.4in. x 0.1in. Given the high density (approx. 10^{10} per cm^2) of elementary screw dislocations (Burgers vector $1c$ with no hollow core) in commercial SiC wafers and epilayers, all appreciable current (greater than 1 A) SiC power devices will likely contain elementary screw dislocations for the foreseeable future. It is therefore important to ascertain the electrical impact of these defects, particularly in high-field vertical...

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